## Search Notes



Application/Control No.	Applicant(s)/Patent Under Reexamination
10534536	FUKUSHIMA ET AL.
Examiner	Art Unit
HENOK G HEYI	2627

SEARCHED			
Class	Subclass	Date	Examiner

SEARCH NOTES			
Search Notes	Date	Examiner	
Searched EAST and consulted with Primary Tan Dinh. Some of the subclasses searched are 369/275.1-4 and 428/64.1-4 (text search only please see search history printout).	01/14/2009	HH	
Search updated.	07/31/2009	HH	
Search updated.	04/27/2010	HH	

INTERFERENCE SEARCH			
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/HENOK G HEYI/ Examiner.Art Unit 2627	

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